



PATENT
Case No. N0099US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)	
)	
Xiangheng Yang)	
)	Group: 3661
Serial No.: 09/929,397)	
)	
Filed: August 14, 2001)	Examiner:
)	
For: Method for Determining the Intersection of)	Thu V. Nguyen
Polygons used to Represent Geographic)	
Features)	

**FIFTH INFORMATION
DISCLOSURE STATEMENT**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Pursuant to 37 C.F.R. §1.56 and in conformance with 37 C.F.R. §§ 1.97-1.99, Applicant discloses the reference(s) listed on the attached form PTO-1449 for consideration by the Examiner.

The undersigned certifies that each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior hereto.

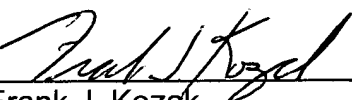
Applicant requests that the Examiner review the entire disclosure of each listed reference. The Examiner is requested to acknowledge consideration of the reference(s) by initialing the appropriate location(s) on the form PTO-1449 enclosed herewith.

Included with the submission of this Information Disclosure Statement is a copy of U.S. Patent No. 6,622,085, which is a translation of PCT WO00/43953 (Japanese).

Applicant submits that the claimed subject matter of the present application defines over the cited prior art.

Applicant does not represent any cited reference to be prior art and Applicant reserves the right to disqualify any reference by the showing of an earlier date of invention, if appropriate.

Respectfully submitted,



Frank J. Kozak
Reg. No. 32,908
Attorney for Applicant

NAVTEQ North America, LLC
(Formerly NAVIGATION TECHNOLOGIES CORPORATION)
222 Merchandise Mart Plaza, Suite 900
Chicago, Illinois 60654
(312) 894-7000

FORM PTO-1449	SERIAL NO. 09/929,397	CASE NO. N0099US
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	FILING DATE 08/14/2001	GROUP ART UNIT 3661
(use several sheets if necessary)		APPLICANT(S): X. Yang

REFERENCE DESIGNATION			U.S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
	A1	6622085	9/16/2003	Amita et al.	701/208	

FOREIGN PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES NO
	A2	WO00/43953	7/27/2000	WIPO	G06T 1/00	x

EXAMINER INITIAL	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)	
	A3	Yang Y. et al., "An efficient scanning pattern for layered manufacturing processes", Proceedings of the 2001 IEEE International Conference on Robotics and Automation, ICRA 2001, Seoul, Korea 5/21-26/2001, pp. 1340-1345.
	A4	EP 02255634 Search Report, dated 10/27/2004

EXAMINER	DATE CONSIDERED
----------	-----------------

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.